

Excelitas' C30659-1550E InGaAs APD Preamplifier Modules exhibit enhanced damage threshold and greater resilience when exposed to higher optical power densities.

Excelitas Technologies' C30659 Series includes a Si or InGaAs Avalanche Photodiode (APD) with a hybrid preamplifier, in the same hermetically-sealed TO-8 package, to allow for ultra-low noise operation.

The Si APDs used in these devices are the same as used in Excelitas' C30817EH, C30902EH, C30954EH and C30956EH products, while the InGaAs APDs are used in the C30645EH and C30662EH products. These detectors provide very good response between 830 and 1550 nm and very fast rise- and fall-times at all wavelengths. The preamplifier section of the module uses a very low noise GaAs FET front end designed to operate at higher transimpedance than Excelitas' regular C30950 Series.

The C30659 series features an inverting amplifier design with an emitter follower used as an output buffer stage. It remains pin-to-pin compatible with the C30950 Series. To obtain the wideband characteristics, the output of these devices should be capacitively- or AC-coupled to a 50  $\Omega$  termination. The module must not be DCcoupled to loads of less than 2 k $\Omega$ . For field use, it is recommended that a temperature-compensated HV supply be employed to maintain a constant responsivity over temperature.

Excelitas' InGaAs C30659-1550E Preamplifier Modules, with 1550 nm peak response, are designed to exhibit higher damage thresholds, thus providing greater resilience when exposed to high optical power densities.

Customization of the C30659 Series of APD Preamplifier Modules is available to meet your specific design challenges; modifications include bandwidth and gain optimization, use of different APDs, FC-connectorized packaging.

#### www.excelitas.com C30659 Series-Rev.1.7-2017.07 Page 1 of 10

#### **Key Features**

- System bandwidths of 50 and 200MHz
- Ultra low noise equivalent power (NEP)
- Spectral response range: With Si APD: 400 to 1100 nm
  - o With InGaAs APD: 1100 to 1700 nm
- Typical power consumption: 150 mW
- ±5 V amplifier operating voltages
- 50 Ω AC load capability (AC-Coupled)
- Hermetically-sealed TO-8 package
- High reliability
- Fast overload recovery
- Pin-to-pin compatible with the C30950
- Light entry angle, over 130°
- Model 1550E exhibits enhanced damage threshold
- RoHS-compliant

#### Applications

- IIDAR
- Range finding
- Laser designation
- Confocal microscopy
- High-speed, extreme low-light detection
- Distributed temperature sensing (DTS)
- Analytical instrumentation
- High-speed, free-space optical communication



### Table 1. Performance Specifications – C30659-900 Models (900 nm peak response Si APD)

Test conditions: Case temperature = 22°C,  $V_{amp}$  = ±5 V, HV =  $V_{op}$  (see Note 1),  $R_L$  = 50  $\Omega$  AC coupled

Detector Type	<b>C30659-900-R8AH</b> (C30817EH APD)			<b>C30659-900-R5BH</b> (C30902EH APD)			
Parameter	Min	Typical	Max	Min	Typical	Max	Units
Active diameter		0.8			0.5		mm
Active area		0.5			0.2		mm²
Nominal field of view $\alpha$ (see Figure 8)		147			148		Degrees
Nominal field of view $\alpha'$ (see Figure 8)		151			151		Degrees
System bandwidth, f <sub>-3dB</sub>	40	50		175	200		MHz
Bandwidth range		50			200		MHz
Temperature coefficient of Vop for constant gain		2.2			0.7		V/°C
$V_{op}$ for specified responsivity	275	Note 1	435	180	Note 1	260	V
Temperature sensor sensitivity (Note 2)	-1.8	-2.1	-2.4	-1.8	-2.1	-2.4	mV/°C
Responsivity at 830 nm at 900 nm R <sub>f</sub> (Internal feedback resistor)		2700 3000 82			460 400 12		kV/W kV/W kΩ
Noise equivalent power (NEP) (Note 3) Average from 100 kHz to f <sub>-3dB</sub> , Δf = 1.0 Hz at 830 nm at 900 nm Output spectral noise voltage Averaged from 100 kHz to f <sub>-3dB</sub>		14 12 35	17 15 45		35 40 15	55 65 25	fW/√Hz fW/√Hz nV/√Hz
Output impedance	33	40	50	33	40	50	Ω
Rise time, t <sub>r</sub> (λ = 830 and 900 nm) 10% to 90% points		7			2		ns
Fall time, t <sub>f</sub> (λ = 830 and 900 nm) 90% to 10% points		7			2		ns
Recovery time after overload (Note 4)			150			150	ns
Output voltage swing (1 k $\Omega$ load) (Note 5)	2	3		2	3		$V_{pp}$
Output voltage swing (50 $\Omega$ load) (Note 5)	0.7	0.9		0.7	0.9		V <sub>pp</sub>
DC output offset voltage	-1	0.25	1	-1	0.25	1	$V_{\text{DC}}$
Positive supply current (V+)		20	35		20	35	mA
Negative supply current (V <sub>-</sub> )		10	20		10	20	mA

### Notes:

1. A specific value of  $V_{op}$  is supplied with each device. The  $V_{op}$  value will be within the specified range.

2.  $I_f = 0.1 \text{ mA at } 25^{\circ}\text{C}.$ 

3. NEP is calculated as the output spectral noise voltage divided by the typical responsivity.

4. 0 dBm with 250 ns pulses.

5. Pulsed operation, AC-coupled.

### Table 2. Performance Specifications – C30659-1060 Models (1060 nm optimized response Silicon APD) Test conditions: Case temperature = 22°C, $V_{amp} = \pm 5$ V, HV = $V_{op}$ (see Note 1), $R_L = 50 \Omega$ AC coupled

Detector type	<b>C30659-1060-3AH</b> (C30956EH APD)			<b>C30659-1060-R8BH</b> (C30954EH APD)			
Parameter	Min	Typical	Мах	Min	Typical	Max	Units
Active diameter		3.0			0.8		mm
Active area		7.1			0.5		mm²
Nominal field of view $\alpha$ (see Figure 8)		136			149		Degrees
Nominal field of view $\alpha'$ (see Figure 8)		154			153		Degrees
System bandwidth, f <sub>-3dB</sub>	40	50		175	200		MHz
Bandwidth range		50			200		MHz
Temperature coefficient of $V_{op}$ for constant gain		2.2			2.2		V/°C
$V_{op}$ for specified responsivity	275	Note 1	425	275	Note 1	425	V
Temperature sensor sensitivity (Note 2)	-1.8	-2.1	-2.4	-1.8	-2.1	-2.4	mV/°C
Responsivity at 900 nm at 1064 nm R <sub>f</sub> (Internal feedback resistor)		450 280 22			370 200 12		kV/W kV/W kΩ
Noise equivalent power (NEP) (Note 3) Average from 100 kHz to f <sub>-3dB</sub> , Δf = 1.0 Hz at 900 nm at 1064 nm Output spectral noise voltage Averaged from 100 kHz to f <sub>-3dB</sub>		55 90 25	90 125 35		55 100 20	80 150 30	fW/√Hz fW/√Hz nV/√Hz
Output impedance	33	40	50	33	40	50	Ω
Rise time, t <sub>r</sub> (λ = 900 and 1064 nm) 10% to 90% points		7			2		ns
Fall time, t <sub>f</sub> (λ = 900 and 1064 nm) 90% to 10% points		7			2		ns
Recovery time after overload (Note 4)			150			150	ns
Output voltage swing (1 k $\Omega$ load) (Note 5)	2	3		2	3		$V_{pp}$
Output voltage swing (50 $\Omega$ load) (Note 5)	0.7	0.9		0.7	0.9		$V_{pp}$
DC output offset voltage	-1	0.25	1	-1	0.25	1	VDC
Positive supply current (V+)		20	35		20	35	mA
Negative supply current (V <sub>-</sub> )		10	20		10	20	mA

#### Notes:

1. A specific value of  $V_{\text{op}}$  is supplied with each device. The  $V_{\text{op}}$  value will be within the specified range.

2.  $I_f = 0.1 \text{ mA at } 25^{\circ}\text{C}.$ 

3. NEP is calculated as the output spectral noise voltage divided by the typical responsivity.

4. 0 dBm with 250 ns pulses.

5. Pulsed operation, AC-coupled

### Table 3. Performance Specifications – C30659-1550/1550E Models (1550 nm peak response InGaAs APD) Test conditions: Case temperature = 22°C, $V_{amp} = \pm 5$ V, HV = $V_{op}$ (see Note 1), $R_L = 50 \Omega$ AC coupled

Detector type		<b>C30659-1550-R2AH</b> <b>C30659-1550E-R2AH</b> (C30662EH APD)			C30659-1550-R08BH C30659-1550E-R08BH (C30645EH APD)			
Parameter	Min	Typical	Max	Min	Typical	Max	Units	
Active diameter		0.2			0.08		mm	
Active area		0.03			0.005		mm²	
Nominal field of view $\alpha$ (see Figure 8)		145			145		Degrees	
Nominal field of view $\alpha'$ (see Figure 8)		146			146		Degrees	
System bandwidth, f-3dB	40	50		175	200		MHz	
Bandwidth range		50			200		MHz	
Temperature coefficient of V <sub>op</sub> for constant gain		0.2			0.2		V/°C	
V <sub>op</sub> for specified responsivity	40	Note 1	70	40	Note 1	70	V	
Temperature sensor sensitivity (Note 2)	-1.8	-2.1	-2.4	-1.8	-2.1	-2.4	mV/°C	
Responsivity at 1300 nm at 1550 nm R <sub>f</sub> (Internal feedback resistor)		300 340 68			80 90 18		kV/W kV/W kΩ	
Noise equivalent power (NEP) (Note 3) Average from 100 kHz to f <sub>-3dB</sub> , Δf = 1.0 Hz at 1300 nm at 1550 nm Output spectral noise voltage Averaged from 100 kHz to f <sub>-3dB</sub>		150 130 45	180 160 55		250 220 20	375 330 30	fW/√Hz fW/√Hz nV/√Hz	
Output impedance	33	40	50	33	40	50	Ω	
Rise time, t <sub>r</sub> (λ = 1300 and 1550 nm) 10% to 90% points		7			2		ns	
Fall time, $t_f$ ( $\lambda$ = 1300 and 1550 nm) 90% to 10% points		7			2		ns	
Recovery time after overload (Note 4)			150			150	ns	
Output voltage swing (1 k $\Omega$ load) (Note 5)	2	3		2	3		$V_{pp}$	
Output voltage swing (50 $\Omega$ load) (Note 5)	0.7	0.9		0.7	0.9		$V_{pp}$	
DC output offset voltage	-1	0.25	1	-1	0.25	1	VDC	
Positive supply current (V+)		20	35		20	35	mA	
Negative supply current (V <sub>-</sub> )		10	20		10	20	mA	

Notes:

- 1. A specific value of  $V_{op}$  is supplied with each device. The  $V_{op}$  value will be within the specified range.
- 2. If = 0.1 mA at 25°C.
- 3. NEP is calculated as the output spectral noise voltage divided by the typical responsivity.
- 4. 0 dBm with 250 ns pulses.
- 5. Pulsed operation, AC-coupled.

### Table 4. Absolute – Maximum Ratings, Limiting Values

Detector type	<b>C30659-900-R8AH</b> (Silicon APD)		<b>C30659-900-R5BH</b> (Silicon APD)		<b>C30659-1060 Models</b> (Silicon APD)		C30659-1550(E) Models (InGaAs APD)			
Parameter	Min	Max	Min	Max	Min	Max	Min	Max	Units	
Photodiode bias voltage (Note 1)										
at $T_A = +70^{\circ}C$		600		350		600		100	V	
at $T_A = -40^{\circ}C$		300		210		300		50	V	
Incident radiant flux, $\Phi_M$ , (Note 2)										
average (Note 3)		0.1		0.1		0.1		2	mW	
peak (Note 4)		50		50		50			mW	
peak (Note 5)							4 (for -1550) 1000 (for 1550E)		kW/cm²	
Case temperature										
storage, T <sub>stg</sub>	-50	100	-50	100	-50	100	-50	100	°C	
operating, $T_A$	-40	70	-40	70	-40	70	-40	70	°C	
Preamplifier bias voltage	±4.5	±5.5	±4.5	±5.5	±4.5	±5.5	±4.5	±5.5	V	

#### Notes:

1. The operating voltage (V<sub>op</sub>) must remain below the breakdown voltage (V<sub>br</sub>), these values are worst-case estimates. HV voltage current should be limited externally to less than 1 mA.

2. As demonstrated in laboratory conditions.

3. Based on 0.5 W electrical power on the high voltage (HV) supply.

4. Test with 50 ns pulse width.

5. Tested at 1064 nm, 10 ns pulse width and 1 kHz pulse repetition rate.

### Figure 1. Schematic Block Diagram – C30659 Series









### Figure 5. Typical Noise and Frequency response curves



### Output voltage noise normalization is calculated using the following formula:

$$V_{n_{normalize}} = \frac{V_n}{V_{n_{average}}}, \text{ where } V_{n_{average}} \left[\frac{V}{\sqrt{Hz}}\right] = \sqrt{\frac{\int_{-3dB}^{f_{-3dB}} V_n^2 \cdot df}{\int_{-3dB}}}$$



#### Figure 6. Typical variation of responsivity as a function of temperature

### Figure 7. Mechanical Characteristics – C30659 Series – reference dimensions shown in mm [inches]



AND ARE FOR REFERENCE ONLY

VS-380R3

### Figure 8. Approximate field of view – C30659 Series

HV, APD BIAS

NC

CASE

4

5

6

10

11

12

For incident radiation at angles  $\leq \alpha/2$ , the photosensitive surface is totally illuminated. For incident radiation at angles >  $\alpha/2$ , but  $\leq \alpha'/2$ , the photosensitive surface is partially illuminated.

GND, DC RETURNS

NC

+5V (+Vamp)



### Table 5 – Ordering guide

Model	Nominal Bandwidth	Wavelength Response	Detector Type	Detector Material	Active Diameter	Comments
C30659-900-R8AH	50 MHz	900 nm	C30817EH	Silicon	0.8 mm	
C30659-900-R5BH	200 MHz	(peak)	C30902EH		0.5 mm	
С30659-1060-ЗАН	50 MHz	1064 nm	C30956EH		3.0 mm	
C30659-1060-R8BH	200 MHz	(optimized)	C30954EH		0.8 mm	
C30659-1550-R2AH	50 MHz	1550 nm	C30662EH	InGaAs	0.2 mm	
C30659-1550E-R2AH		(peak)				Enhanced damage threshold
C30659-1500-R08BH	200 MHz		C30645EH		0.08 mm	
C30659-1550E-R08BH						Enhanced damage threshold

#### **RoHS Compliance**

The C30659 Series of APD Preamplifier Modules are designed and built to be fully compliant with the European Union Directive 2011/65/EU – Restriction of the use of certain Hazardous Substances (RoHS) in Electrical and Electronic equipment.



### **About Excelitas Technologies**

Excelitas Technologies is a global technology leader focused on delivering innovative, customized solutions to meet the lighting, detection and other high-performance technology needs of OEM customers.

Excelitas has a long and rich history of serving our OEM customer base with optoelectronic sensors and modules for more than 45 years beginning with PerkinElmer, EG&G, and RCA. The constant throughout has been our innovation and commitment to delivering the highest quality solutions to our customers worldwide.

From aerospace and defense to analytical instrumentation, clinical diagnostics, medical, industrial, and safety and security applications, Excelitas Technologies is committed to enabling our customers' success in their specialty end-markets. Excelitas Technologies has approximately 5,000 employees in North America, Europe and Asia, serving customers across the world.

Excel	itas '	Techno	logies

22001 Dumberry Road Vaudreuil-Dorion, Quebec Canada J7V 8P7 Telephone: (+1) 450.424.3300 Toll-free: (+1) 800.775.6786 Fax: (+1) 450.424.3345 detection.na@excelitas.com Excelitas Technologies GmbH & Co. KG Wenzel-Jaksch-Str. 31 D-65199 Wiesbaden Germany Telephone: (+49) 611 492 430 Fax: (+49) 611 492 165 detection.europe@excelitas.com Excelitas Technologies International Sales Office Bat HTDS BP 246, 91882 Massy Cedex, France Telephone: +33 (1) 6486 2824 europedefense@excelitas.com Excelitas Technologies Singapore, Pte. Ltd. 8 Tractor Road Singapore 627969 Telephone: (+65) 6775 2022 (Main number) Telephone: (+65) 6770 4366 (Customer Service) Fax: (+65) 6778-1752 detection.asia@excelitas.com



For a complete listing of our global offices, visit www.excelitas.com/locations

© 2013 Excelitas Technologies Corp. All rights reserved. The Excelitas logo and design are registered trademarks of Excelitas Technologies Corp. All other trademarks not owned by Excelitas Technologies or its subsidiaries that are depicted herein are the property of their respective owners. Excelitas reserves the right to change this document at any time without notice and disclaims liability for editorial, pictorial or typographical errors.